# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Mamitsu, et al.

Serial No.: 10/699,837

Filed: November 4, 2003

Title: SEMICONDUCTOR DEVICE HAVING RADIATION STRUCTURE

Atty. Dkt.: 01-103-CON3

Art Unit: 2822

Examiner: Roy Karl Potter

Allowed: March 28, 2005 Confirmation No.: 5581

Commissioner for Patents Arlington, VA 22202

Mail Stop Issue Fee

Date: April 5, 2005

### CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this correspondence is being facsimile transmitted to the United States Patent and Trademark Office, Fax No. 703-872-9306 on April 5, 2005 to the attention of Examiner Roy Karl Potter of AU 2822.

Typed Name: DAVID G. POSZ

Signature:

## **REQUEST FOR RETURN OF INITIALED FORM PTO-1449**

Sir:

Pursuant to MPEP §609, Applicant hereby respectfully requests that the Examiner initial the enclosed copies of the Forms PTO-1449, originally submitted concurrently with the filing of the present application, in the appropriate place in the left-hand column as proof that the listed references have been considered and made of record. Applicant further requests that the Examiner return copies of the initialed forms to the undersigned at his earliest convenience.

Respectfully submitted,

David G. Posz

Reg. No. 37,701

DGP/moa Posz Law Group, PLC 12040 South Lakes Drive Suite 101 Reston, VA 20191 (703) 707-9110 Customer No. 23400

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JUN 1 6: 2005 2	APPLICANT	MAMITSU et al.		
Z. S.	FILING DATE	Nov. 4, 2003	GROUP	

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	APPLICANT	MAMITSU et al.		
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	4,646,129	Feb. 24, 1987	Yerman et al		
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